BLIP TESTING PROCEDURE CDMS 8 Oct. 1998
VAMP/LOCKIN:BOARD # _____ STATUS _____ DATE _____
V AMP 1:

1. Test connections:
   - For the **V AMP test** measure the V AMP output at PS1 VAMP OUT, and MUX 1 MON connectors on the front panel.
   - For the **VAMP/LOCKIN test** observe the LOCKIN output at LOCKIN 1 OUT on front panel and LOCKIN 1 output on the Breakout Box.
   - PS1 Bias in conjunction with a detector simulator(a resistor divider network and a FET circuit contained within the breakout box), will provide the input signal.

2. **Power up settings**:

LOCKIN BYPASS 1:	0(off)
AZ FAST:	1(on)
V AMP FAST:	1(on)
EXT REF 1:	0(off)

3. **Test preparation settings:**

readfile vamp.macro			
Set DAC = 1V	*PS1DAC(1)*	PS1 DAC OUT:	1V
Select the 1kHz ref.:	*refPS1(0)*	REF SELECT:	0
Filter output:	*filterPS1*	FILTER:	1(on)
Undivide output:	*divPS1(0)*	DIVIDE:	0(off)
Unground QI:	*gndPS1(0)*	GND PS1:	0(off)
Unselect variable input:	*varPS1(0)*	VARIABLE INPUT:	0(off)
Select Mux 1 output:	*Mux1(Vamp1)*		

4. **V AMP test:**
Input settings in Step 3 before starting test.

Turn Phonon Sensor 1 pot. on BOB fully clockwise

For manual input testing:
Vin = 1Vp-p sine wave
Enter the following settings: *PS1DAC(0)*
VarPS1

Vamp out = 1Vp-p

```
Is PS1 VAMP OUT a 1kHz sine wave?  _____
What is the maximum amplitude of VAMP OUT?  _____
```

Change the potentiometer setting randomly over its range of travel.

```
Does the amplitude of PS1 VAMP OUT change?  _____
Are the Vamp and Mux outputs equal?  _____
```

5. **VAMP/LOCKIN test:**
Input settings in Step 3 and verify step 4 results before starting test.

Vary pot setting and observe LOCKIN 1 OUT.

```
Does LOCKIN 1 OUT level change in amplitude with
   corresponding changes in the pot setting?  _____
```

If "NO" then conduct LOCKIN TEST procedures.

Turn on Lockin Bypass: ***bypass***

Does the LOCKIN 1 OUT change to a sine wave? _____

Turn off Lockin Bypass: *bypass(0)* Verify return of original output

V AMP 2:

1. Test connections:
    - For the **V AMP test** measure the V AMP output at PS2 VAMP OUT, and MUX 1 MON connectors on the front panel.
    - For the **VAMP/LOCKIN test** observe the LOCKIN output at LOCKIN 2 OUT on front panel and LOCKIN 2 output on the Breakout Box.
    - PS2 Bias in conjunction with a detector simulator(a resistor divider network and a FET circuit contained within the breakout box), will provide the input signal.

Set mux 1 to output PS2 VAMP OUT: ***Mux1(Vamp2)***

2. **Power up settings**:

LOCKIN BYPASS 2:	0(off)
AZ FAST:	1(on)
V AMP FAST:	1(on)
EXT REF 2:	0(off)

3. **Test preparation settings:**

readfile vamp.macro		PS2 DAC OUT:	1V
Set DAC = 1V	***PS2DAC(1)***	REF SELECT:	0
Select the 1kHz ref.:	***refPS2(0)***	FILTER:	1(on)
Filter output:	***filterPS2***	DIVIDE:	0(off)
Undivide output:	***divPS2(0)***	GND PS2:	0(off)
Unground QI:	***gndPS2(0)***	VARIABLE INPUT:	0(off)
Unselect variable input:	***varPS2(0)***		
Select Mux 2 output:	*Mux2(Vamp2)*		

4. **V AMP test:**
Input settings in Step 3 before starting test.

For manual input testing:
Vin = 1Vp-p sine wave
Enter the following settings: *PS1DAC(0)*
VarPS1
Vamp out = 1Vp-p

Turn Phonon Sensor pot. on BOB fully clockwise

Is PS2 VAMP OUT a 1kHz sine wave? _____
What is the maximum amplitude of VAMP OUT? _____

Change the potentiometer setting randomly over its range of travel.

BLIP TESTING PROCEDURE   CDMS   8 Oct. 1998
VAMP/LOCKIN:BOARD # _____ STATUS _____ DATE _____

`Does the amplitude of PS2 VAMP OUT change?  _____`
`Are the Vamp and Mux outputs equal?  _____`

5. **VAMP/LOCKIN test:**
Input settings in Step 3 and verify step 4 results before starting test.

Vary pot setting and observe LOCKIN 2 OUT.

`Does LOCKIN 2 OUT level change in amplitude with`
`   corresponding changes in the pot setting?  _____`
If "NO" then conduct LOCKIN TEST procedures.

Turn on Lockin Bypass: ***bypass***

`Does the LOCKIN 2 OUT change to a sine wave?  _____`

Turn off Lockin Bypass: *bypass(0)*